

Cp E 432: Testing of Computing Systems

Physical defects from semiconductor manufacture, fault modeling and simulation, fault activation and detection in digital systems, digital test pattern synthesis, test coverage, test compaction, online/offline/BIST testing concepts, design-for-test, design-for- manufacture, system testability and diagnosability. 3 Credits

Prerequisites

- El E 351: Electronics Circuits I
- El E 385: Advanced Digital Systems
- El E 386: Advanced Digital Systems Laboratory

Instruction Type(s)

Lecture: Lecture for Cp E 432

Subject Areas

<u>Computer Engineering, General</u>

Related Areas

<u>Computer Hardware Engineering</u>

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